Data Driven I-V Freature Extraction for PV modules

Paper presentation

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Motivation

- Performance parameter extracted from I-V data set: Pmp, Voc, Isc, Rs, Rsh, FF are essential for diagnosing degradation of PV modules
- Data driven technique can be applied to a large amount of data in a short time in contrast with traditional fitting of diode equation
- Applied to 2.2 million real I-V datasets, took 3 hrs to complete
- No requirement of device parameter to be input from the researcher
- Applicable on non standard I-V datasets having multiple steps

Method

- Fit smoothing spline on raw I-V dataset (unequal speaing in voltage) to get 500 equal spaced points in voltage
- Regression performed on moving window of 5 consecutive I-V points
- Slope of each regression line is used to identify either step or MPPT
- Identify the segments (steps): Steeper slope on the left than right
- If step is found, I-V feature is extracted separately for both the parts